

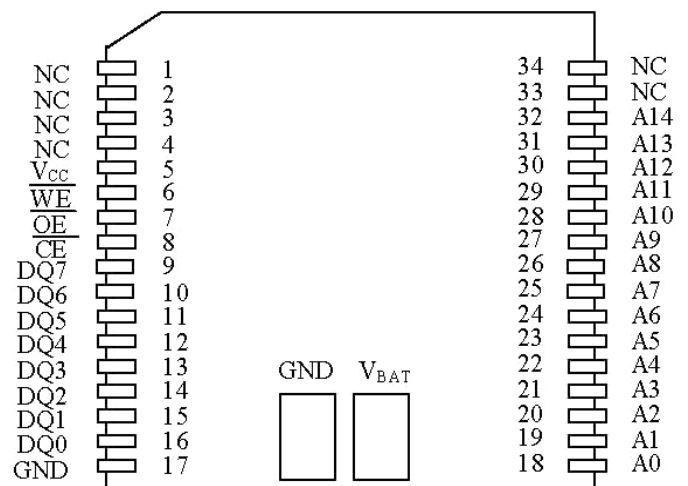
FEATURES

- 10 years minimum data retention in the absence of external power
- Data is automatically protected during power loss
- Replaces 32k x 8 volatile static RAM, EEPROM or Flash memory
- Unlimited write cycles
- Low-power CMOS
- Read and write access times as fast as 100ns
- Lithium energy source is electrically disconnected to retain freshness until power is applied for the first time
- Optional industrial temperature range of -40 to +85 , designated IND
- JEDEC standard 28-pin DIP package
- PowerCap Module (PCM) package
 - Directly surface-mountable module
 - Replaceable snap-on PowerCap provides lithium backup battery
 - Standardized pinout for all nonvolatile SRAM products
 - Detachment feature on PowerCap allows easy removal using a regular screwdriver

PIN ASSIGNMENT

A14	1	28	V _{CC}
A12	2	27	WE
A7	3	26	A13
A6	4	25	A8
A5	5	24	A9
A4	6	23	A11
A3	7	22	OE
A2	8	21	A10
A1	9	20	CE
A0	10	19	DQ7
DQ0	11	18	DQ6
DQ1	12	17	DQ5
DQ2	13	16	DQ4
GND	14	15	DQ3

28-Pin Encapsulated Package
740-Mil Extended



34-Pin PowerCap Module (PCM)
(Uses DS9034PC PowerCap)

PIN DESCRIPTION

A0-A14	-Address Inputs
DQ0-DQ7	-Data In/Data Out
CE	-Chip Enable
WE	-Write Enable
OE	-Output Enable
V _{CC}	-Power (+3.3V)
GND	-Ground
NC	-No Connect

DESCRIPTION

The DS1230W 3.3V 256k Nonvolatile SRAM is a 262, 144-bit, fully static, nonvolatile SRAM organized as 32,768 words by 8 bits. Each NV SRAM has a self-contained lithium energy source and control circuitry, which constantly monitors Vcc for an out-of-tolerance condition. When such a condition occurs, the lithium energy source is automatically switched on and write protection is unconditionally enabled to prevent data corruption. DIP-package DS1230W devices can be used in place of existing 32k x 8 static RAMs directly conforming to the popular byte-wide 28-pin DIP standard. The DIP devices also match the pinout of 28256 EEPROMs, allowing direct substitution while enhancing performance. DS1230W devices in the PowerCap Module package are directly surface mountable and are normally paired with a DS9034PC PowerCap to form a complete Nonvolatile SRAM Module. There is no limit on the number of write cycles that can be executed and no additional support circuitry is required for microprocessor interfacing.

READ MODE

The DS1230W executes a read cycle whenever \overline{WE} (Write Enable) is inactive (high) and \overline{CE} (Chip Enable) and \overline{OE} (Output Enable) are active (low). The unique address specified by the 15 address inputs (A0-A14) defines which of the 32,768 bytes of data is to be accessed. Valid data will be available to the eight data output drivers within t_{ACC} (Access Time) after the last address input signal is stable, providing that \overline{CE} and \overline{OE} (Output Enable) access times are also satisfied. If \overline{OE} and \overline{CE} access times are not satisfied. Then data access must be measured from the later-occurring signal (\overline{CE} or \overline{OE}) and the limiting parameter is either t_{CO} for \overline{CE} or t_{OE} or t_{OE} for \overline{OE} rather than address access.

WRITE MODE

The DS1230W executes a write cycle whenever the \overline{WE} and \overline{CE} signals are active (low) after address inputs are stable. The later-occurring falling edge of \overline{CE} or \overline{WE} will determine the start of the write cycle. The write cycle is terminated by the earlier rising edge of \overline{CE} or \overline{WE} . All address inputs must be kept valid throughout the write cycle. \overline{WE} must return to the high state for a minimum recovery time (t_{WR}) before another cycle can be initiated. The \overline{OE} control signal should be kept inactive (high) during write cycles to avoid bus contention. However, if the output drivers are enabled (\overline{CE} and \overline{OE} active) then \overline{WE} will disable the outputs in t_{ODW} from its falling edge.

DATA RETENTION MODE

The DS1230W provides full functional capability for Vcc greater than 3.0 volts and write protects by 2.8 volts. Data is maintained in the absence of Vcc without any additional support circuitry. The nonvolatile static RAMs constantly monitor Vcc. Should the supply voltage decay, the NV SRAMs automatically write protect themselves, all inputs become "don't care," and all outputs become high-impedance. As Vcc falls below approximately 2.5 volts, a power switching circuit connects the lithium energy source to RAM to retain data. During power-up, when Vcc rises above approximately 2.5 volts, the power switching circuit connects external Vcc to RAM and disconnects the lithium energy source. Normal RAM operation can resume after Vcc exceeds 3.0 volts.

FRESHNESS SEAL

Each DS1230W device is shipped from Dallas Semiconductor with its lithium energy source disconnected, guaranteeing full energy capacity. When Vcc is first applied at a level greater than 3.0 volts, the lithium energy source is enabled for battery back-up operation.

PACKAGES

The DS1230W is available in two packages: 28-pin DIP and 34-pin PowerCap Module (PCM). The 28-pin DIP integrates a lithium battery, an SRAM memory and a nonvolatile control function into a single package with a JEDEC-standard, 600-mil DIP pinout. The 34-pin PowerCap Module integrates SRAM memory and nonvolatile control into a module base along with contacts for connection to the lithium battery in the DS9034PC PowerCap. The PowerCap Module package design allows a DS1230W to be surface mounted without subjecting its lithium backup battery to destructive high-temperature reflow soldering. After a DS1230W module base is reflow soldered, a DS9034PC PowerCap is snapped on top of the base to form a complete Nonvolatile SRAM module. The DS9034PC is keyed to prevent improper attachment. DS1230W module bases and DS9034PC PowerCaps are ordered separately and shipped in separate containers. See the DS9034PC data sheet for further information.

ABSOLUTE MAXIMUM RATINGS*

Voltage on Any Pin Relative to Ground	-0.3V to +4.6V
Operating Temperature	0 to 70 , -40 to +85 for IND parts
Storage Temperature	-40 to +70 , -40 to +85 for IND parts
Soldering Temperature	260 for 10 seconds

* This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operation sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods of time may affect reliability.

RECOMMENDED DC OPERATING CONDITIONS

(t_A: See Note 10)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Power Supply Voltage	V _{CC}	3.0	3.3	3.6	V	
Logic 1	V _{IH}	2.2		V _{CC}	V	
Logic 0	V _{IL}	0.0		0.4	V	

DC ELECTRICAL CHARACTERISTICS

(t_A: See Note 10) (V_{CC}=3.3V ±0.3V)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Input Leakage Current	I _{IL}	-1.0		+1.0	μA	
I/O Leakage Current $\overline{CE} \geq V_{IH} \leq V_{CC}$	I _{IO}	-1.0		+1.0	μA	
Output Current @2.2V	I _{OH}	-1.0			mA	
Output Current @ 0.4V	I _{OL}	2.0			mA	
Standby Current $\overline{CE}=2.2V$	I _{CCS1}		50	250	μA	
Standby Current $\overline{CE}=V_{CC}-0.2V$	I _{CCS2}		30	150	μA	
Operating Current	I _{CCO1}			50	mA	
Write Protection Voltage	V _{TP}	2.8	2.9	3.0	V	

CAPACITANCE

(t_A=25)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Input Capacitance	C _{IN}		5	10	pF	
Input/Output Capacitance	C _{I/O}		5	10	pF	

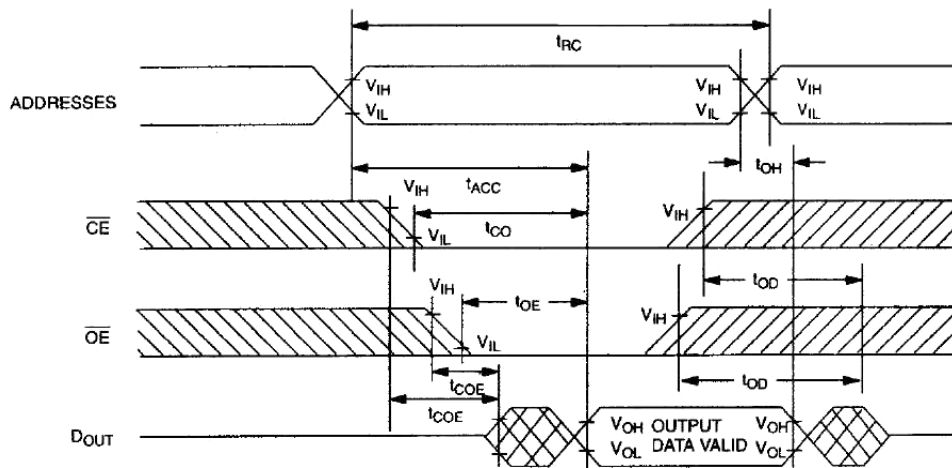
AC ELECTRICAL CHARACTERISTICS

(t_A: See Note 10) (V_{CC}=3.3V ±0.3V)

PARAMETER	SYMBOL	DS1230W-100	DS1230W-150	UNITS	NOTES
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		MIN	MAX	MIN	MAX		
Read Cycle Time	t_{RC}	100		150		ns	
Access Time	t_{ACC}		100		150	ns	
OE to Output Valid	t_{OE}		50		70	ns	
CE to Output Valid	t_{CO}		100		150	ns	
OE or CE to Output Active	t_{COE}	5		5		ns	5
Output High Z from Deselection	t_{OD}		35		35	ns	5
Output Hold from Address Change	t_{OH}	5		5		ns	
Write Cycle Time	t_{WC}	100		150		ns	
Write Pulse Width	t_{WP}	75		100		ns	3
Address Setup Time	t_{AW}	0		0		ns	
Write Recovery Time	t_{WR1}	5		5		ns	12
	t_{WR2}	20		20		ns	13
Output High Z from \overline{WE}	t_{ODW}		35		35	ns	5
Output Active from \overline{WE}	t_{OEW}	5		5		ns	5
Data Setup Time	t_{DS}	40		60		ns	4
Data Hold Time	t_{DH1}	0		0		ns	12
	t_{DH2}	20		20		ns	13

READ CYCLE



The diagram shows the timing of a write operation to a 256K16 DRAM. The signals and their timing parameters are as follows:

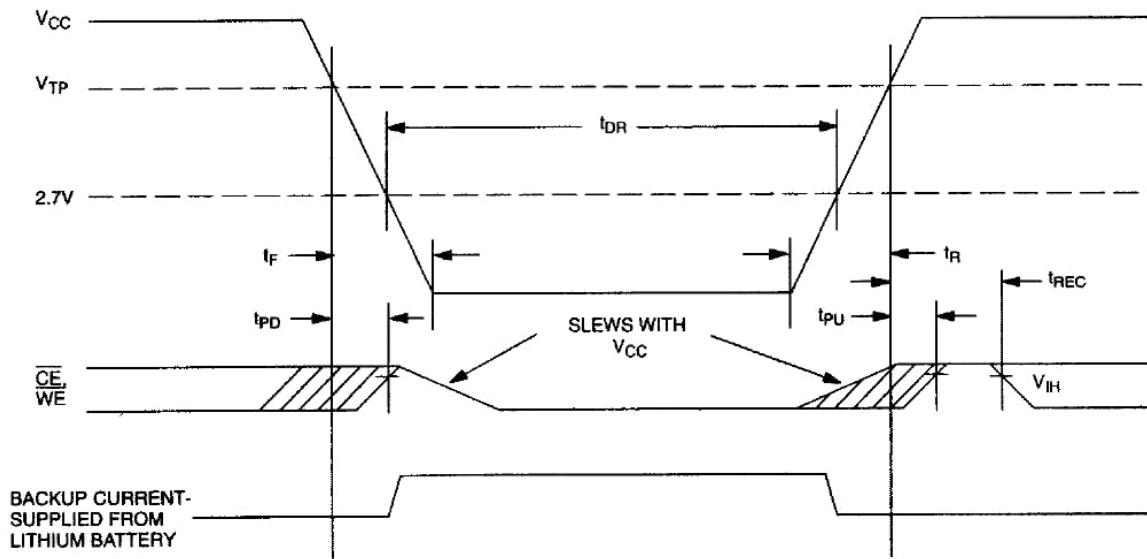
- ADDRESSES:** Shows the address bus with high (V_{IH}) and low (V_{IL}) voltage levels. The total write cycle time is t_{WC} . The address setup time before the write enable pulse is t_{AW} .
- CE (Chip Enable):** A pulse that is active-low. The data output (D_{OUT}) is valid during this pulse. The time from the start of the CE pulse to the start of the write pulse is t_{ODW} .
- WE (Write Enable):** A pulse that is active-low. The time from the start of the WE pulse to the start of the data input (D_{IN}) is t_{WP} . The time from the end of the WE pulse to the end of the data input is t_{WR1} .
- DOUT (Data Output):** The data output bus, which is in a high-impedance state during the write operation. The time from the start of the WE pulse to the start of the data input is t_{ODW} .
- DIN (Data Input):** The data input bus, which is stable during the write operation. The time from the start of the WE pulse to the start of the data input is t_{WP} . The time from the end of the WE pulse to the end of the data input is t_{WR1} .
- Timing Parameters:**
 - t_{WC} : Total write cycle time.
 - t_{AW} : Address setup time before the write enable pulse.
 - t_{WP} : Write pulse width.
 - t_{WR1} : Write recovery time.
 - t_{ODW} : Output delay time from CE to DOUT.
 - t_{OEWE} : Output enable time from WE to DOUT.
 - t_{DS} : Data setup time before the write enable pulse.
 - t_{DH1} : Data hold time after the write enable pulse.

The diagram illustrates the timing relationships for a 256K16B2 DRAM. It shows the following signals and parameters:

- ADDRESSES:** The address bus signal, showing high (V_{IH}) and low (V_{IL}) levels. The total write cycle time is t_{WC} .
- CE (Chip Enable):** An active-low signal. The time from the falling edge of CE to the start of the write cycle is t_{AW} . The time from the rising edge of CE to the end of the write cycle is t_{WR2} .
- WE (Write Enable):** An active-low signal. The time from the falling edge of WE to the start of the write cycle is t_{COE} . The time from the rising edge of WE to the end of the write cycle is t_{OPW} .
- DOUT:** The data output bus, shown with a hexagonal symbol indicating data transfer.
- DiN:** The data input bus, shown with a hexagonal symbol indicating data transfer.
- DATA IN STABLE:** A label indicating the period during which the data input is stable.
- Timing Parameters:**
 - t_{WC} : Total write cycle time.
 - t_{AW} : Address to write enable delay.
 - t_{WP} : Write pulse width.
 - t_{WR2} : Write recovery time.
 - t_{COE} : Write enable to output delay.
 - t_{OPW} : Output pulse width.
 - t_{OS} : Output setup time.
 - t_{DH2} : Output hold time.

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POWER-DOWN/POWER-UP CONDITION



POWER-DOWN/POWER-UP TIMING

(t_A : See Note 10)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Vcc Fail Detect to \overline{CE} and \overline{WE} Inactive	t_{PD}			1.5	μs	11
Vcc slew from V_{TP} to 0V	t_F	150			μs	
Vcc slew from 0V to V_{TP}	t_R	150			μs	
Vcc Valid to \overline{CE} and \overline{WE} Inactive	t_{PU}			2	ms	
Vcc Valid to End of Write Protection	t_{REC}			125	ms	

($t_A=25^\circ C$)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Expected Data Retention Time	t_{DR}	10			years	9

WARNING

Under no circumstance are negative undershoots, of any amplitude, allowed when device is in battery backup mode.

NOTES:

1. \overline{WE} is high for a Read Cycle.
2. $\overline{OE} = V_{IH}$ or V_{IL} . If $\overline{OE} = V_{IH}$ during write cycle, the output buffers remain in a high-impedance state.
3. t_{WP} is specified as the logical AND of \overline{CE} and \overline{WE} . t_{WP} is measured from the latter of \overline{CE} or \overline{WE} going low to the earlier of \overline{CE} or \overline{WE} going high.
4. t_{DH} , t_{DS} are measured from the earlier of \overline{CE} or \overline{WE} going high.
5. These parameters are sampled with a 5 pF load and are not 100% tested.
6. If the \overline{CE} low transition occurs simultaneously with or latter than the \overline{WE} low transition, the output buffers remain in a high-impedance state during this period.
7. If the \overline{CE} high transition occurs prior to or simultaneously with the \overline{WE} high transition, the output buffers remain in high-impedance state during this period.
8. If \overline{WE} is low or the \overline{WE} low transition occurs prior to or simultaneously with the \overline{CE} low transition, the output buffers remain in a high-impedance state during this period.
9. Each DS1230W has a built-in switch that disconnects the lithium source until V_{CC} is first applied by the user. The expected t_{DR} is defined as accumulative time in the absence of V_{CC} starting from the time power is first applied by the user.
10. All AC and DC electrical characteristics are valid over the full operating temperature range. For commercial products, this range is 0 to 70 °C. For industrial products (IND), this range is -40 to +85 °C.
11. In a power-down condition the voltage on any pin may not exceed the voltage on V_{CC} .
12. t_{WR1} and t_{DH1} are measured from \overline{WE} going high.
13. t_{WR1} and t_{DH2} are measured from \overline{CE} going high.
14. DS1230 modules are recognized by underwriters Laboratory (U.L.®) under file E99151.

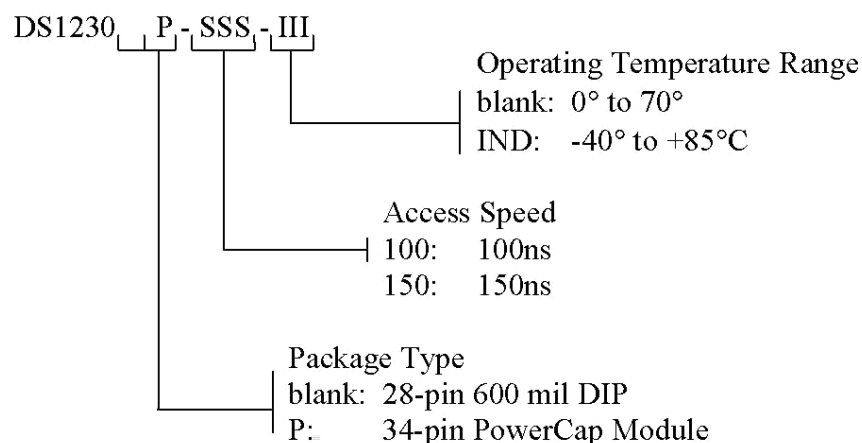
DC TEST CONDITIONS

Outputs Open
Cycle = 200ns for operating current
All voltages are referenced to ground

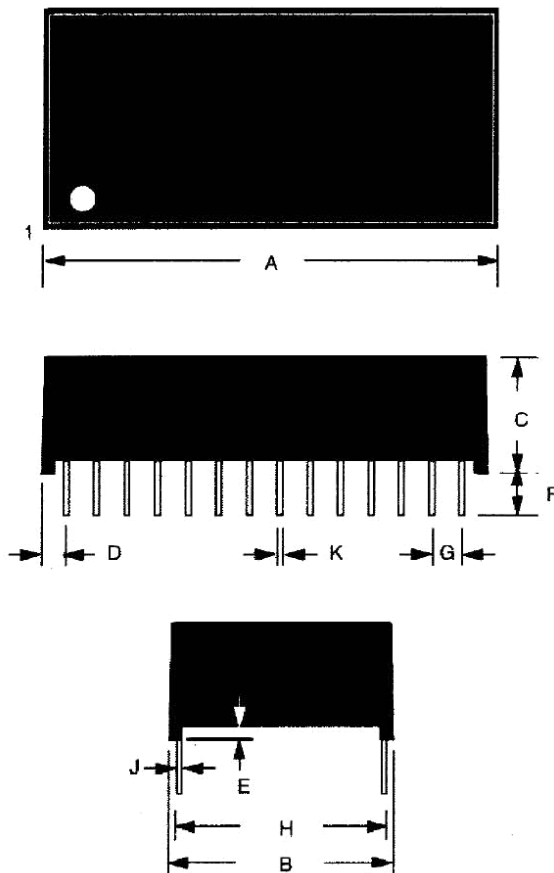
AC TEST CONDITIONS

Output Load: 100pF + 1TTL Gate
Input Pulse Levels: 0 to 2.7V
Timing Measurement Reference Levels
Input: 1.5V
Output: 1.5V
Input pulse Rise and Fall Times: 5ns

ORDERING INFORMATION

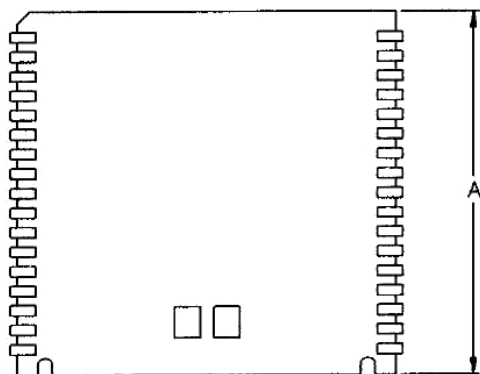


DS1230W NONVOLATILE SRAM, 28-PIN 740-MIL EXTENDED DIP MODULE

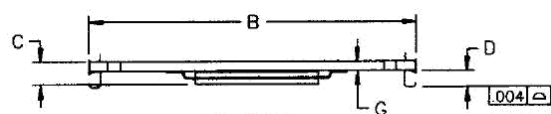


PKG	28-PIN	
DIM	MIN	MAX
A IN.	1.480	1.500
MM	37.60	38.10
B IN.	0.720	0.740
MM	18.29	18.80
C IN.	0.355	0.375
MM	9.02	9.52
D IN.	0.080	0.110
MM	2.03	2.79
E IN.	0.015	0.025
MM	0.38	0.63
F IN.	0.120	0.160
MM	3.05	4.06
G IN.	0.090	0.110
MM	2.29	2.79
H IN.	0.590	0.630
MM	14.99	16.00
J IN.	0.008	0.012
MM	0.20	0.30
K IN.	0.015	0.021
MM	0.38	0.53

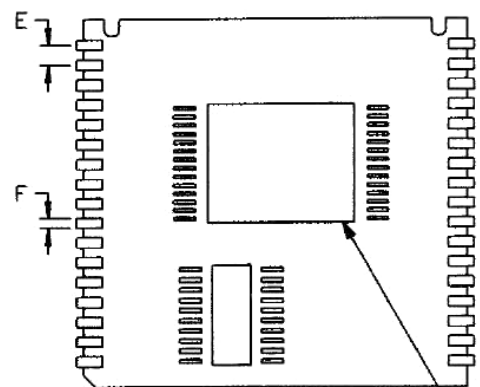
DS1230W NONVOLATILE SRAM, 34-PIN POWERCAP MODULE



TOP VIEW



SIDE VIEW

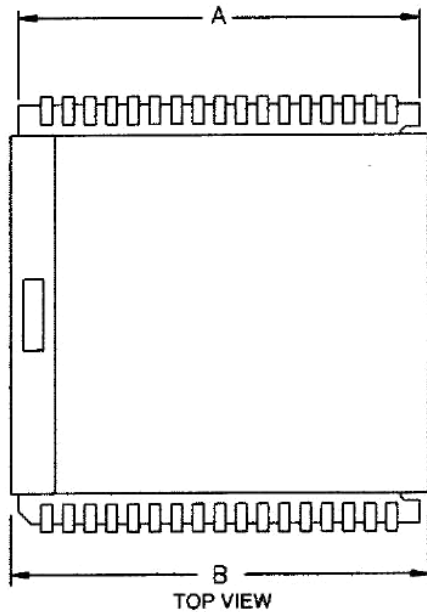


BOTTOM VIEW: REFERENCE ONLY

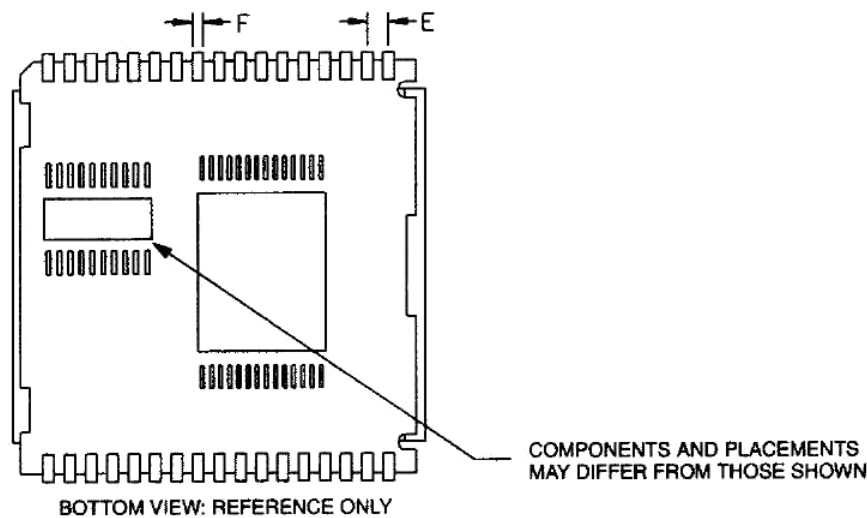
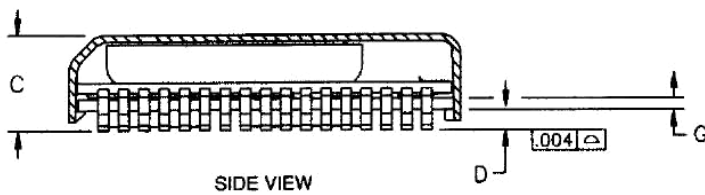
COMPONENTS AND PLACEMENTS
MAY DIFFER FROM THOSE SHOWN

PKG DIM	INCHES		
	MIN	NOM	MAX
A	0.920	0.925	0.930
B	0.980	0.985	0.990
C	-	-	0.080
D	0.052	0.055	0.058
E	0.048	0.050	0.052
F	0.015	0.020	0.025
G	0.020	0.025	0.030

DS1230W NONVOLATILE SRAM, 34-PIN POWERCAP MODULE WITH POWERCAP



PKG DIM	INCHES		
	MIN	NOM	MAX
A	0.920	0.925	0.930
B	0.955	0.960	0.965
C	0.240	0.245	0.250
D	0.052	0.055	0.058
E	0.048	0.050	0.052
F	0.015	0.020	0.025
G	0.020	0.025	0.030



ASSEMBLY AND USE

Reflow Soldering

Artschip Semiconductor recommends that PowerCap Module bases experience on pass through solder reflow oriented label-side up (live-bug).

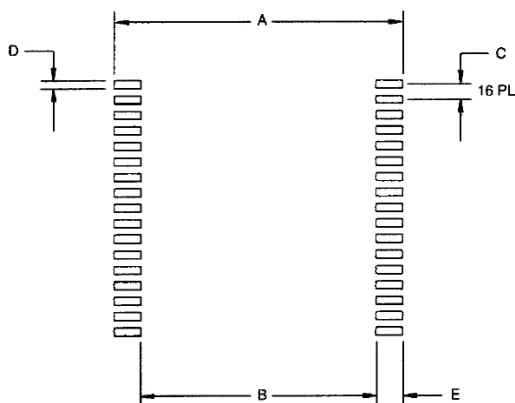
Hand soldering and touch-up

Do not touch soldering iron to leads for more than 3 seconds. To solder, apply flux to the pad, heat the lead frame pad and apply solder. To remove part, apply flux, heat pad until solder reflows, and use a solder wick.

LPM replacement in a socket

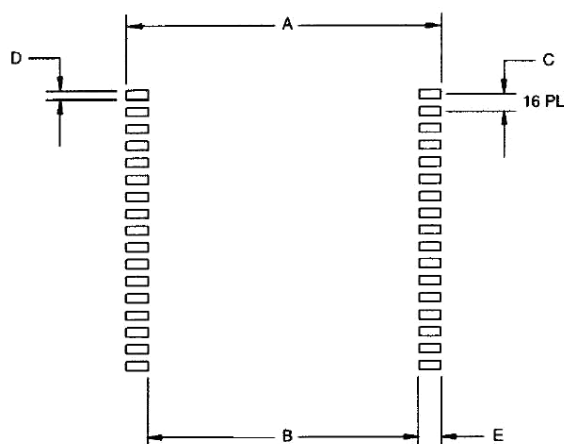
To replace a Low Profile Module in a 68-pin PLCC socket, attach a DS9034PC PowerCap to a module base then insert the complete module into the socket one row of leads at a time, pushing only on the corners of the cap. Never apply force to the center of the device. To remove from a socket, use a PLCC extraction tool and ensure that it does not hit or damage any of the module IC components. Do not use any other tool for extraction.

RECOMMENDED POWERCAP MODULE LAND PATTERN



PKG DIM	INCHES		
	MIN	NOM	MAX
A	-	1.050	-
B	-	0.826	-
C	-	0.050	-
D	-	0.030	-
E	-	0.112	-

RECOMMENDED POWERCAP MODULE SOLDER STENCIL



PKG DIM	INCHES		
	MIN	NOM	MAX
A	-	1.050	-
B	-	0.890	-
C	-	0.050	-
D	-	0.030	-
E	-	0.080	-